MICROPROCESSOR FREE RUN TESTING

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SUMMARY

The objectives of this project were to study the testing methods available when a microcontroller is Free-Running and to apply these methods for fault finding on a microcontroller.

The project is therefore divided into two main parts . The construction of the microcontroller to be tested and the study and application of the fault finding techniques and instruments on this microcontroller .

<u>Construction</u>: The Z80 8-bit family of components was used in the construction because this is superior in both software and hardware capabilities to most 8-bit microcomputer systems on the market. To explore these capabilities apart from the Central Processing Unit (CPU) and Memory , the Z80 Serial (DART) and Parallel (PIO) Input/Output devices and the Z80 Clock Timer Circuit(CTC) were included in the construction. This microcontroller communicates with an ATARI terminal via serial transmission which is enabled using the CTC for the generation of the baud rates and the SIO for the interfacing circuit.

<u>Fault finding techniques and instruments</u>: First, various troubleshooting instruments were examined, starting from the simple hand held instruments and their applications and going to the more sophisticated ones (Logic and Signature Analyser). Next, the techniques were analysed and these included the Free-Run Test and Self Test programs. This microcontroller is capable of testing 2K RAM chips by using certain Self Test routines, an application also examined in the Self Test techniques.

By following the above sequence , the troubleshooting techniques were studied and the Free Run test was carried out being fully aware of hardware and software aspects of the Z80 based system . Also , since the instruments were examined with reference to existing ones in the workshop , the Free Run test was carried out both easier and with more efficiency .

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